

## Supporting Information

### Improved Charge Extraction through Interface Engineering for 10.12%-efficiency and Stable CsPbBr<sub>3</sub> Perovskite Solar Cells

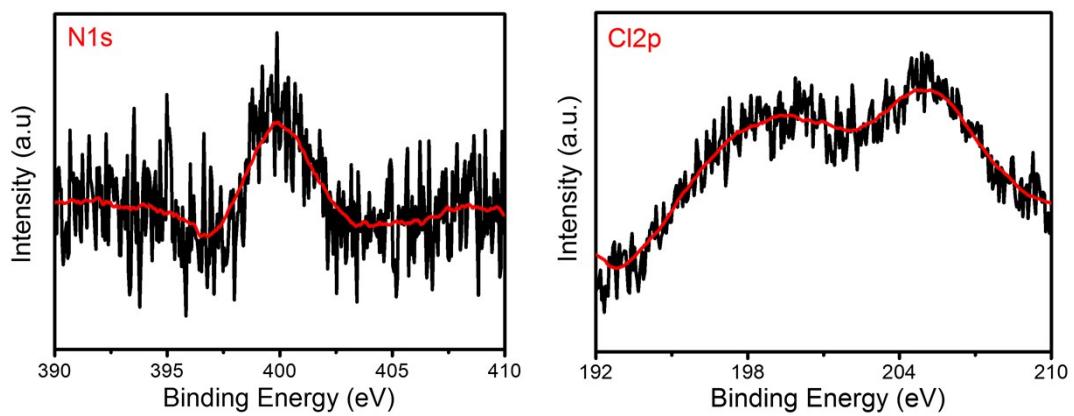
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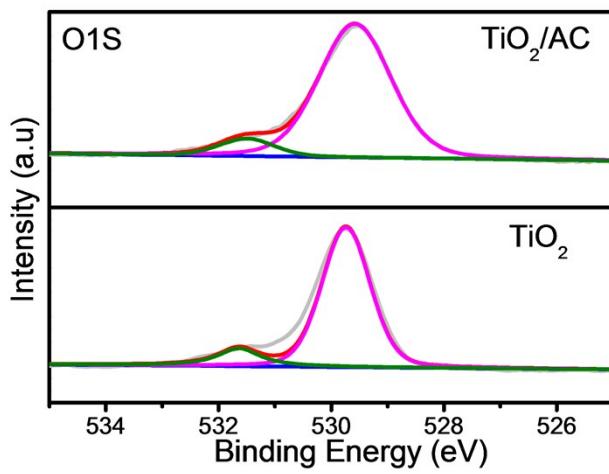
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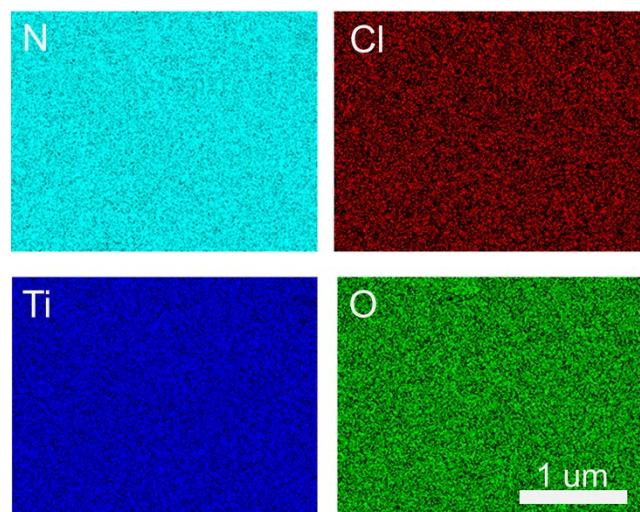
**\* Corresponding Authors.** E-mail: blhe@ouc.edu.cn, tangqunwei@jnu.edu.cn



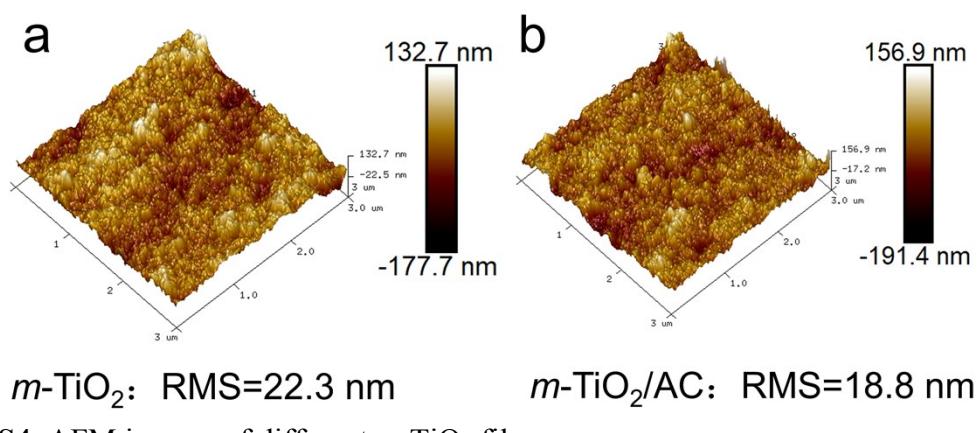
**Fig. S1.** N1s and Cl2p XPS spectra of  $\text{TiO}_2/\text{AC}$  sample.



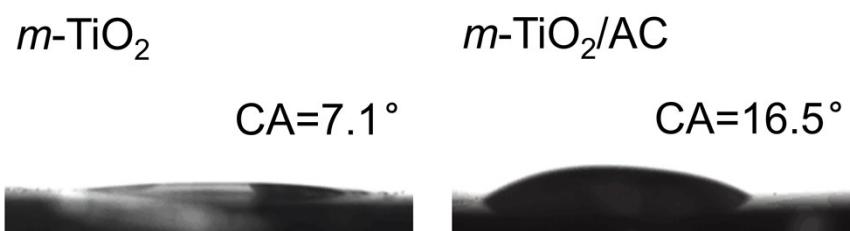
**Fig. S2.** The deconvoluted O1s XPS spectra of different TiO<sub>2</sub> films.



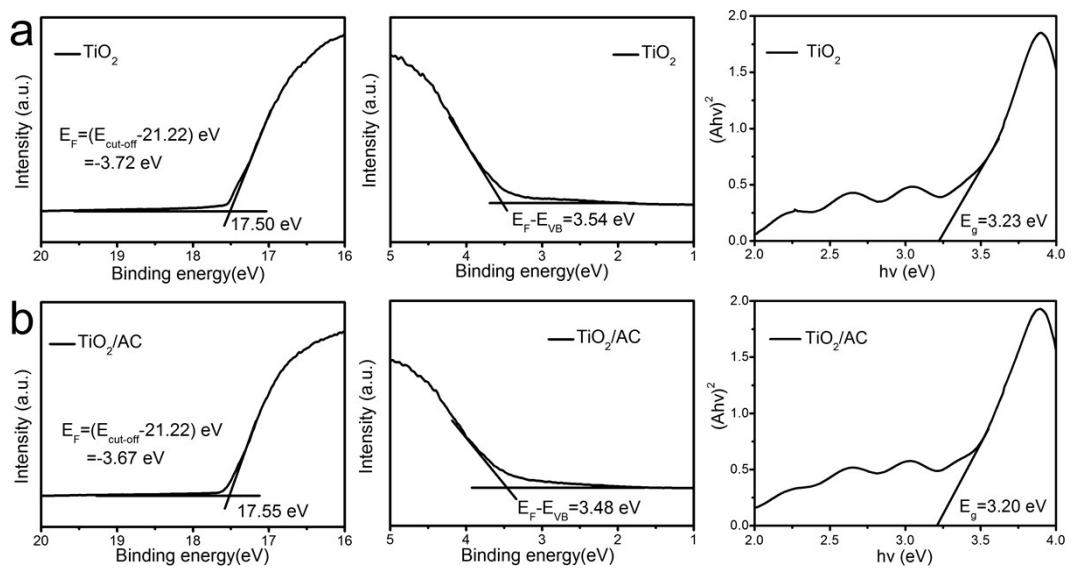
**Fig. S3.** EDS mapping images of N, Cl, Ti and O from *m*-TiO<sub>2</sub>/AC film.



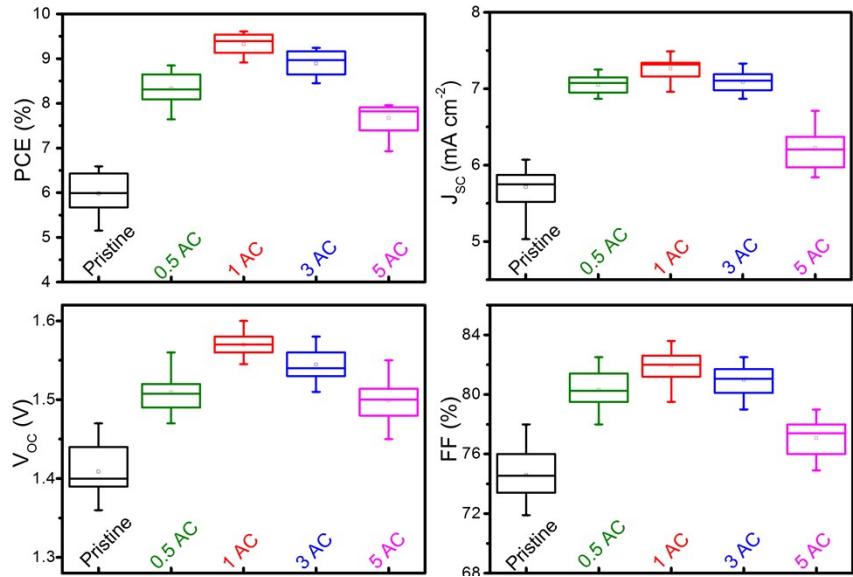
**Fig. S4.** AFM images of different *m*-TiO<sub>2</sub> films.



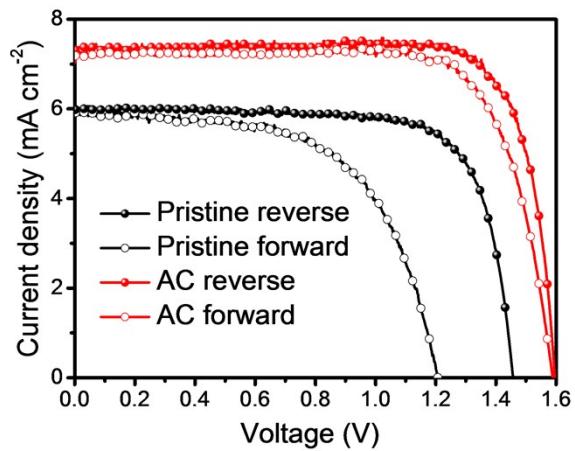
**Fig. S5.** The contact angle of DMF on the different *m*-TiO<sub>2</sub> films.



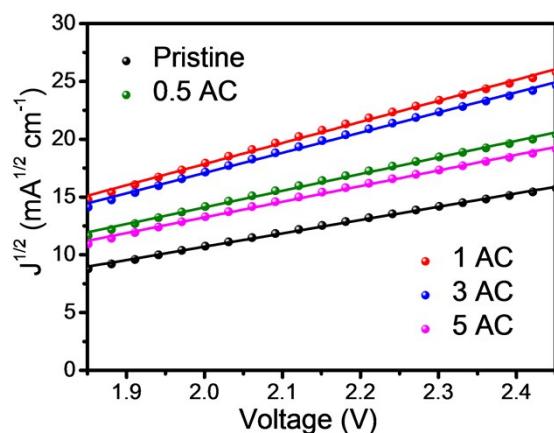
**Fig. S6.** Ultraviolet photoelectron spectra (UPS) and the Tauc plots for various TiO<sub>2</sub> films.



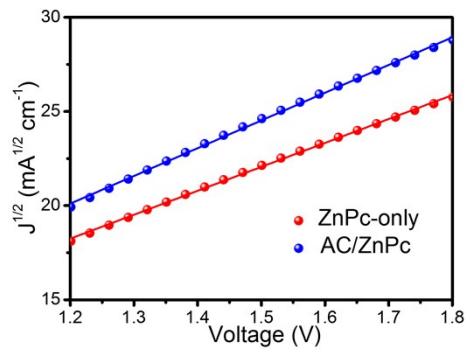
**Fig. S7.** Statistical distribution of PCE,  $J_{SC}$ ,  $V_{OC}$  and FF for thirty random control and AC modified devices.



**Fig. S8.** Hysteresis analysis of control and AC modified  $\text{CsPbBr}_3$  PSCs.



**Fig. S9.** The  $J^{1/2}$ - $V$  curves of the electron-only devices with a structure of FTO/TiO<sub>2</sub>/without or with AC/CsPbBr<sub>3</sub>/PCBM/Carbon.



**Fig. S10.** The  $J^{1/2}$ - $V$  curves of various hole-only devices.

**Table S1.** The FWHM of the main peaks of different PbBr<sub>2</sub> films in XRD.

Planes	(011)	(101)	(111)	(013)	(004)	(201)
PbBr <sub>2</sub>	0.056	0.089	0.125	0.073	0.027	0.136
AC/PbBr <sub>2</sub>	0.073	0.112	0.143	0.082	0.039	0.153

**Table S2.** The  $V_{\text{TFL}}$ ,  $N_t$ ,  $J_D$  and  $\mu_e$  value of various samples.

samples	$V_{\text{TFL}}$ (V)	$N_t(10^{16} \text{ cm}^{-3})$	$J_D(10^{15} \text{ cm}^{-2})$	$\mu_e(10^{-5} \text{ cm}^2 \text{ V}^{-1}\text{s}^{-1})$
Pristine	1.175	1.411	1.32	4.06
0.5 AC	1.136	1.364	2.57	8.11
1 AC	1.094	1.314	6.92	23.20
3 AC	1.125	1.352	5.22	16.80
5 AC	1.162	1.396	1.71	5.32

**Table S3.** The carrier lifetimes obtained from TRPL spectra of various  $\text{CsPbBr}_3$  samples.

Samples	$\tau_{\text{ave}}$ (ns)	$\tau_1$ (ns)	$A_1$ (%)	$\tau_2$ (ns)	$A_2$ (%)
Pristine	0.51	0.34	62.14	2.51	37.86
0.5 AC	0.25	0.15	54.33	1.70	45.67
1 AC	0.18	0.13	67.78	1.15	32.22
3 AC	0.20	0.14	67.02	1.59	32.68
5 AC	0.28	0.17	56.97	1.76	43.03

**Table S4.** The carrier lifetimes obtained from TRPL spectra of various  $\text{CsPbBr}_3$  samples.

Samples	$\tau_{\text{ave}}$ (ns)	$\tau_1$ (ns)	$A_1$ (%)	$\tau_2$ (ns)	$A_2$ (%)
ZnPc-only	0.20	0.14	69.96	1.27	30.04
AC/ZnPc	0.12	0.09	70.32	0.76	29.68